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Application/Control No.	Applicant(s)/Patent under Reexamination				
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257	288,295 310,314 324-326 410,411		
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	DATE	EXMR
EAST search for paper no. 0705 made of record.	7/14/2005	MDP
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Updated EAST search for paper no. 11/05 made of record.	11/14/2005	mdp